

# Abstracts

## An Explicit Solution for the Scattering Parameters of a Linear Two-Port Measured with an Imperfect Test Set (Correspondence)

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*W. Kruppa and K.F. Sodomsky. "An Explicit Solution for the Scattering Parameters of a Linear Two-Port Measured with an Imperfect Test Set (Correspondence)." 1971 Transactions on Microwave Theory and Techniques 19.1 (Jan. 1971 [T-MTT]): 122-123.*

Formulas are derived for the direct calculation of the scattering parameters of a linear two-port, using measurements made on a test set having residual, tracking, and mistermination errors. The problem is formulated by representing the measuring system in terms of scattering parameters. Solutions using this formulation have previously been obtained only in an implicit manner using an iterative approach. The associated calibration procedure is included.

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